

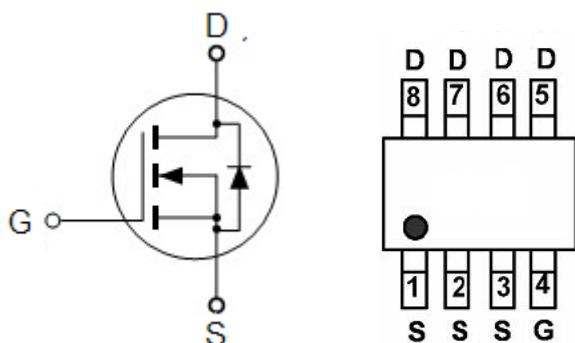


## N-Channel Power MOSFET MEM2502SG

### General Description

MEM2502, the silicon N-channel Enhanced VDMOSFETs, is obtained by the high density Trench technology. Which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is SOP8, which accords with the RoHS standard.

### Pin Configuration



### Features

- Low On-Resistance 60V/16A  
 $R_{DS(ON)} = 7m\Omega @ V_{GS}=10V, I_D=8A$   
 $R_{DS(ON)} = 8.5m\Omega @ V_{GS}=4.5V, I_D=8A$
- Fast switching
- Low gate charge
- Low reverse transfer capacitances
- 100% single pulse avalanche energy test
- Surface mount package:SOP8

### Typical Application

- Power switch circuit of adaptor and charger.

### Maximum Ratings (Ta=25°C)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DSS}$	60	V
Drain Current	$I_D$	$T_A=25^\circ C$	16
		$T_A=100^\circ C$	8
Pulsed Drain Current	$I_{DM}^1$	64	A
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Single Pulse Avalanche Energy	$E_{AS}^2$	320	mJ
Peak Diode Recovery	$dv/dt^3$	3.0	V/ns
Total Power Dissipation	$P_d$	1.78	W
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	150, -55~150	$^\circ C$
Maximum soldering temperature	$T_L$	300	$^\circ C$

## Thermal Characteristics

Parameter	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Ambient <sup>3</sup>	$R_{\theta JA}$	70	$^{\circ}C/W$

## Electrical Characteristics

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	60	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	-	3.0	V
Gate-Body Leakage	$I_{GSS}$	$V_{DS}=0V, V_{GS}=20V$	-	-	100	nA
		$V_{DS}=0V, V_{GS}=-20V$	-	-	-100	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$T_A=25^{\circ}C$ $V_{DS}=60V, V_{GS}=0V$	-	-	1	$\mu A$
		$T_A=125^{\circ}C$ $V_{DS}=48V, V_{GS}=0V$	-	-	100	$\mu A$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=8A$	-	7	10	m $\Omega$
		$V_{GS}=4.5V, I_D=8A$	-	8.5	12	m $\Omega$
Forward Trans conductance	$g_{FS}$	$V_{DS}=15V, I_D=8A$	-	65	-	S
Drain-Source Diode Forward Continuous Current	$I_S$	$V_{GS}=0V$	-	-	16	A
Source-drain (diode forward) voltage	$V_{SD}$	$V_{GS}=0V, I_S=8A$	0.5	-	1.5	V
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=25V,$ $V_{GS}=0V,$ $f=1.0MHz$	-	4398	-	pF
Output Capacitance	$C_{oss}$		-	296	-	
Reverse Transfer Capacitance	$C_{rss}$		-	220	-	
<b>Switching Characteristics</b>						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD}=30V,$ $R_G=9.1\Omega$ $V_{GS}=10V,$ $I_D=8A$	-	25.3	-	ns
Rise Time	$t_r$		-	95.7	-	
Turn-Off Delay Time	$t_{d(off)}$		-	154	-	
Fall-Time	$t_f$		-	77.9	-	
Total Gate Charge	$Q_g$	$V_{DD}=30V,$ $V_{GS}=10V,$ $I_D=8A$	-	88.8	-	nC
Gate-Source Charge	$Q_{gs}$		-	17.3	-	
Gate-Drain Charge	$Q_{gd}$		-	17.4	-	

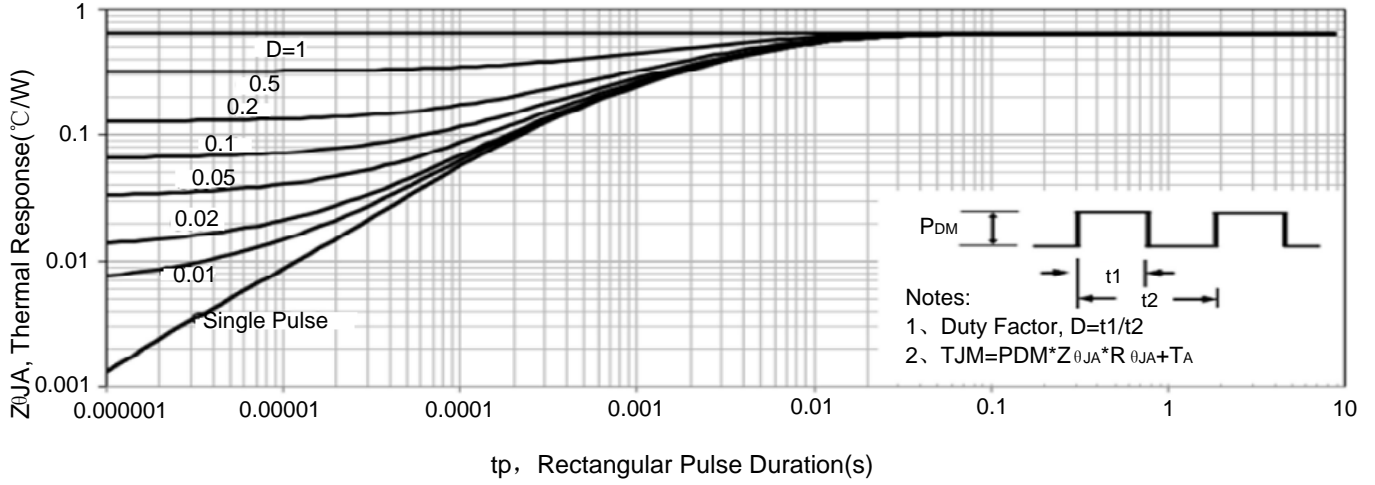
1、Repetitive rating, pulse width limited by junction temperature.

2、 $L=10.0mH, I_D=8A, Start T_J=25^{\circ}C$

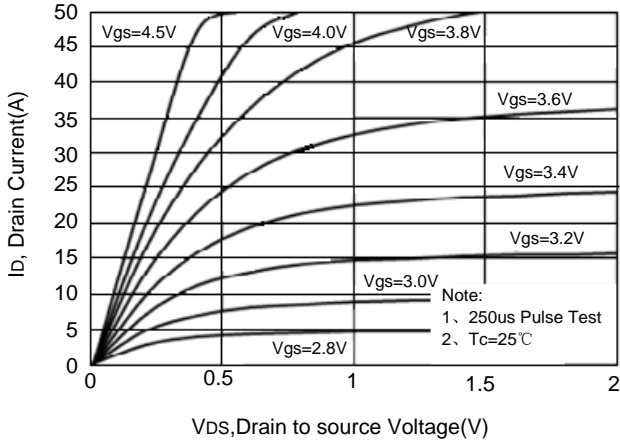
3、 $I_{SD}=8A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, Start T_J=25^{\circ}C$

## Typical performance characteristics

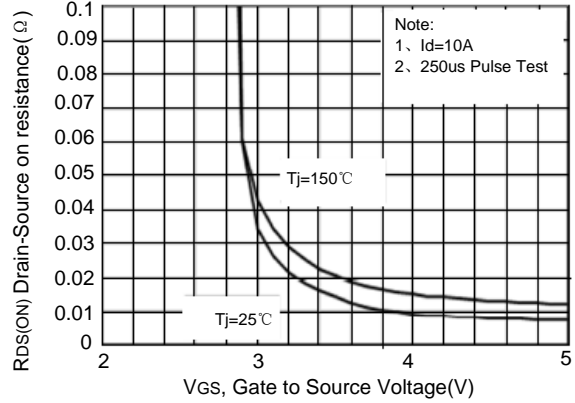
### Maximum Effective Thermal impedance, Junction-to-Ambient



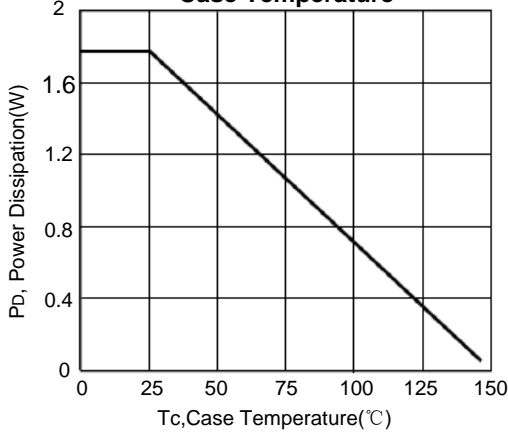
### On-State Characteristics



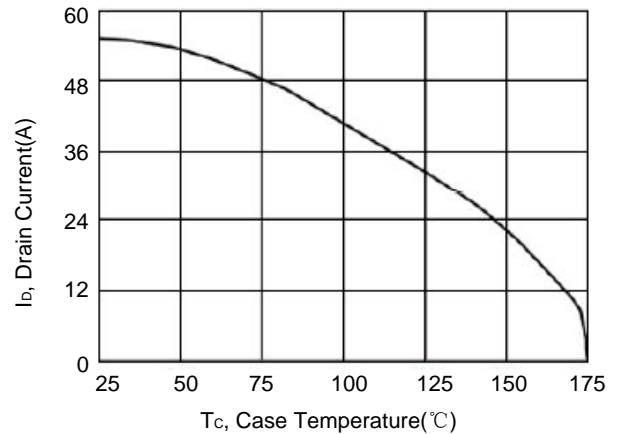
### Normalized On-Resistance vs. VGS



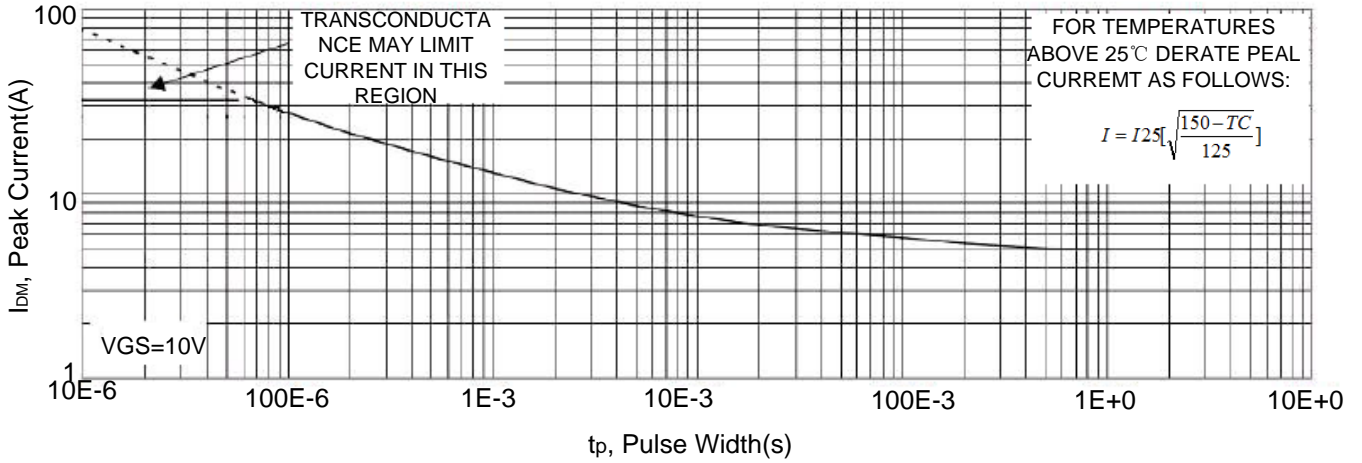
### Maximum Power Dissipation vs Case Temperature



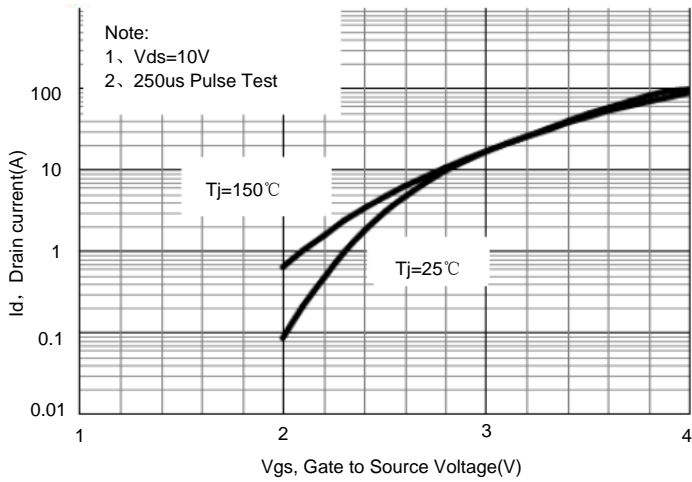
### Maximum Continuous Drain Current vs Case Temperature



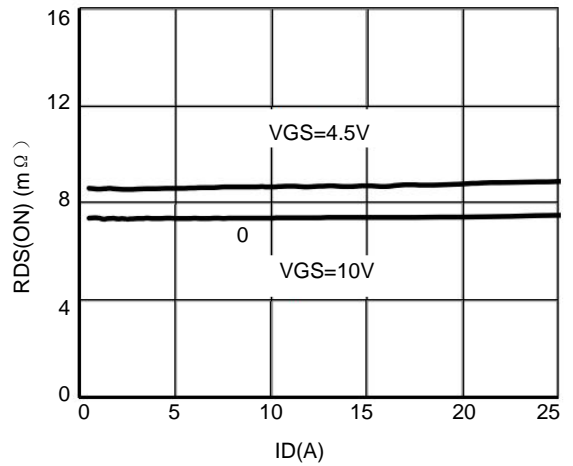
## Maximum Peak Current Capability



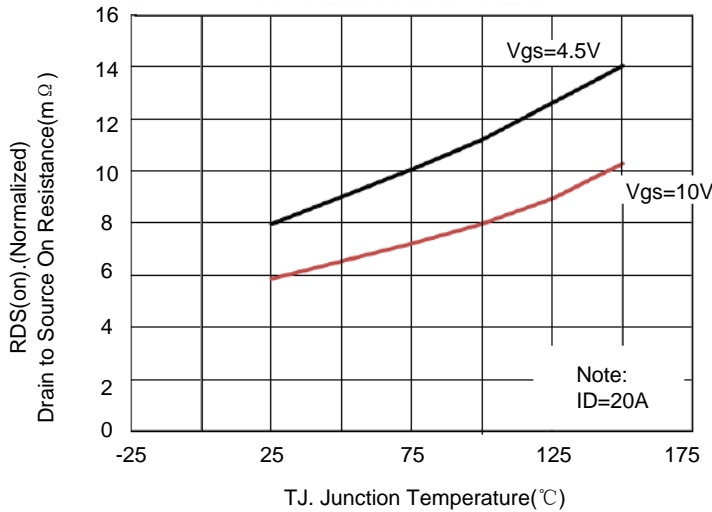
### Typical Transfer Characteristics



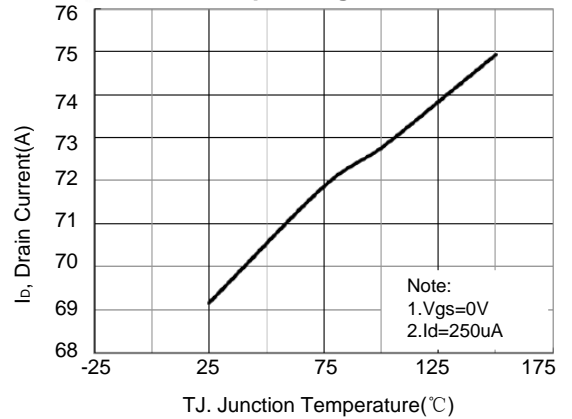
### Typical Drain to Source ON Resistance vs Drain Current



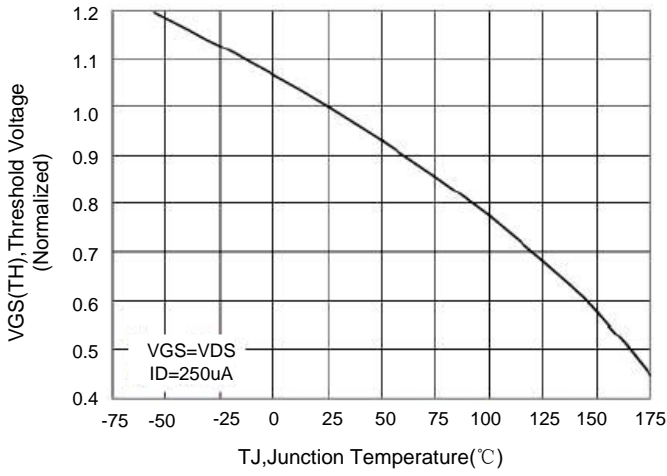
### Typical Drain to Source ON Resistance vs Junction Temperature



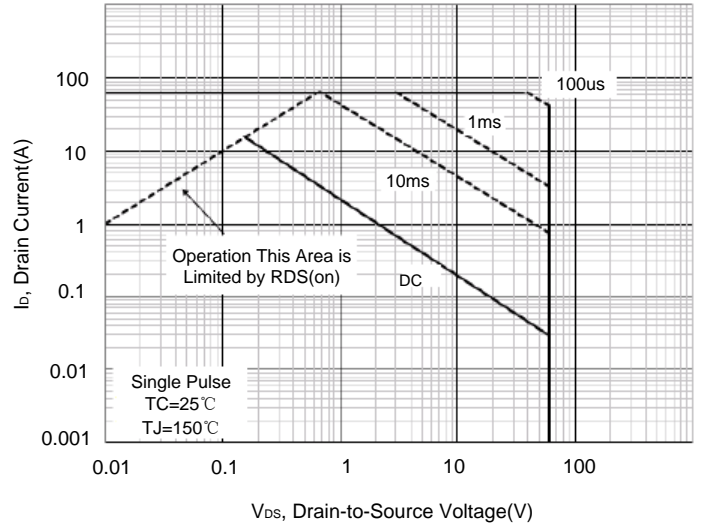
### Maximum Forward Bias Safe Operating Area



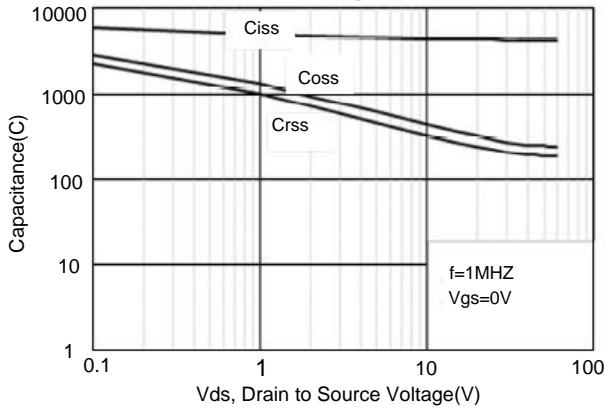
**Typical Threshold Voltage vs Junction Temperature**



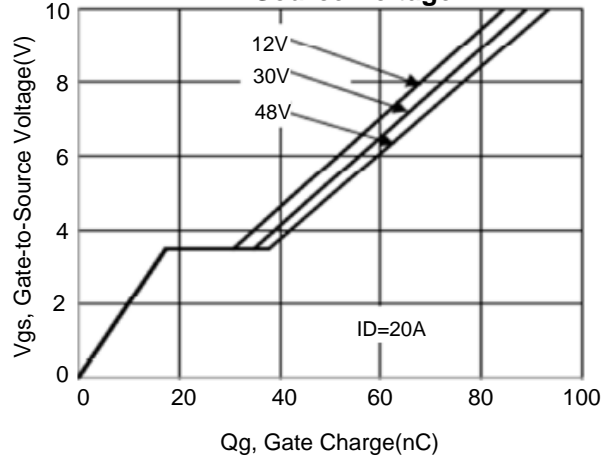
**Maximum Forward Bias Safe Operating Area**



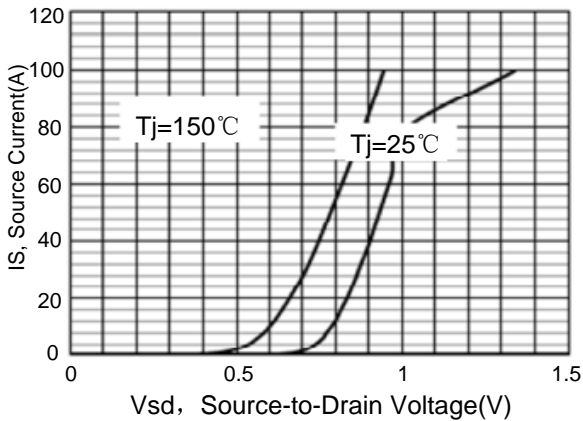
**Typical Capacitance vs Drain-to-Source Voltage**



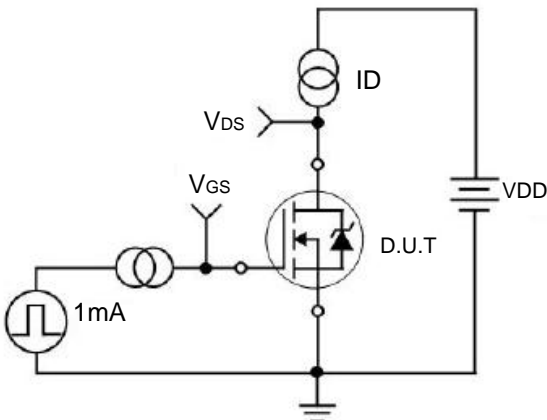
**Typical Gate Charge vs Gate-to-Source Voltage**



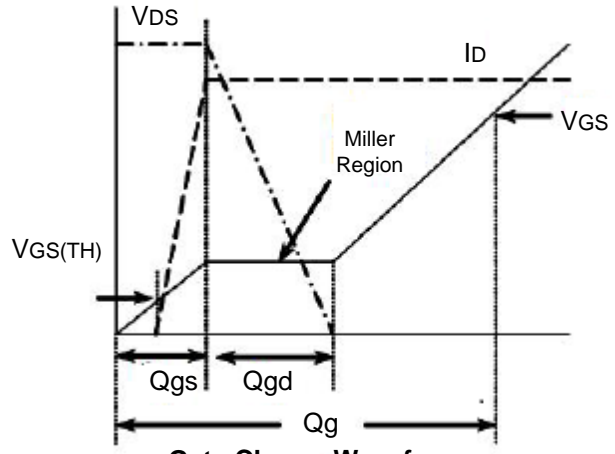
**Typical Body Diode Transfer Characteristics**



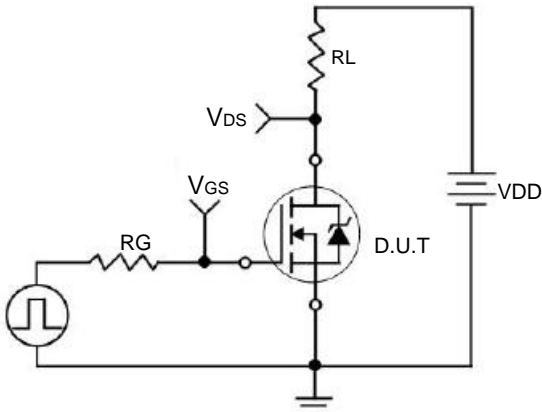
## Test Circuit and Waveform



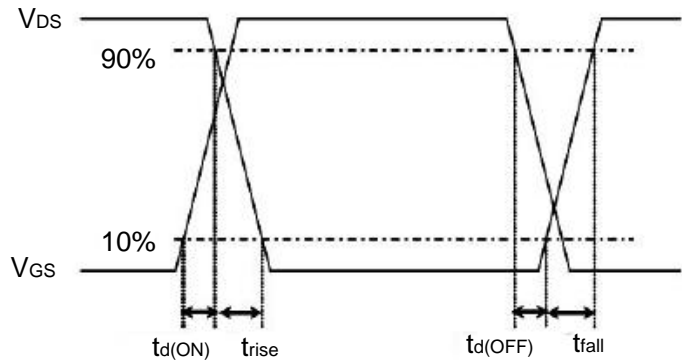
**Gate charge Test Circuit**



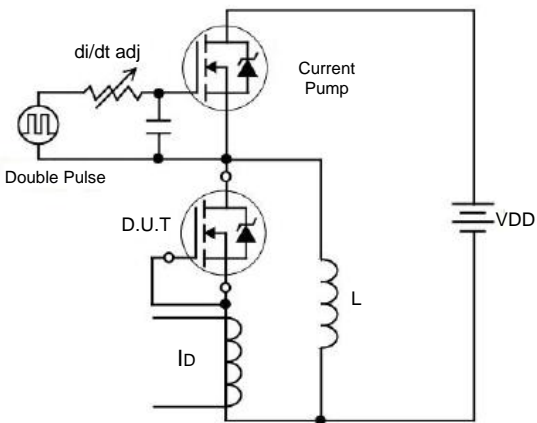
**Gate Charge Waveform**



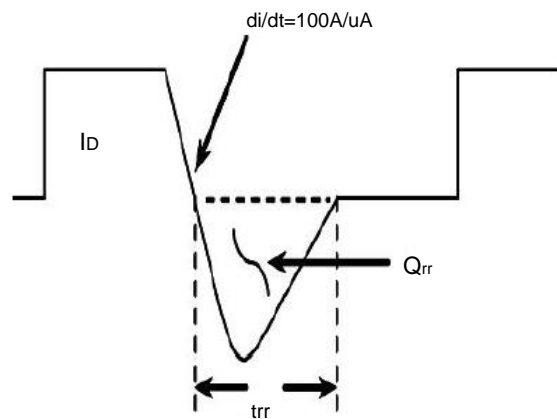
**Resistive Switching Test Circuit**



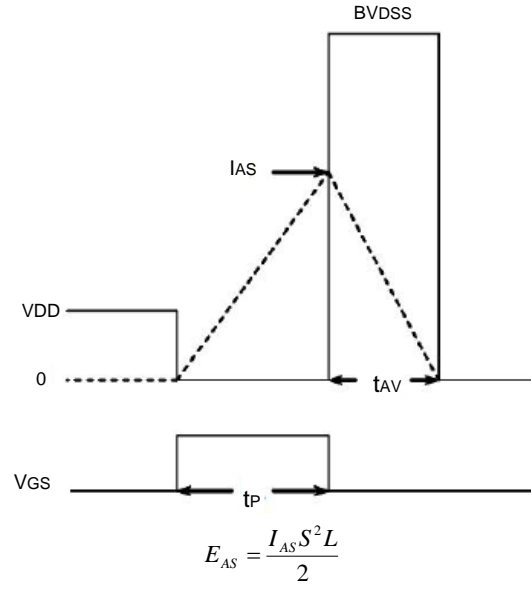
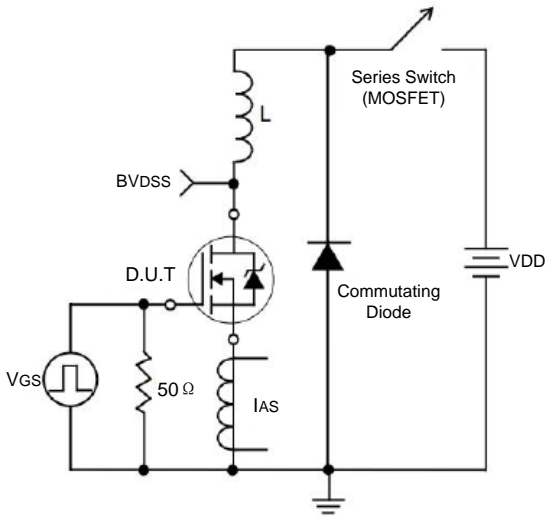
**Resistive Switching Waveforms**



**Diode Reverse Recovery Test Circuit**



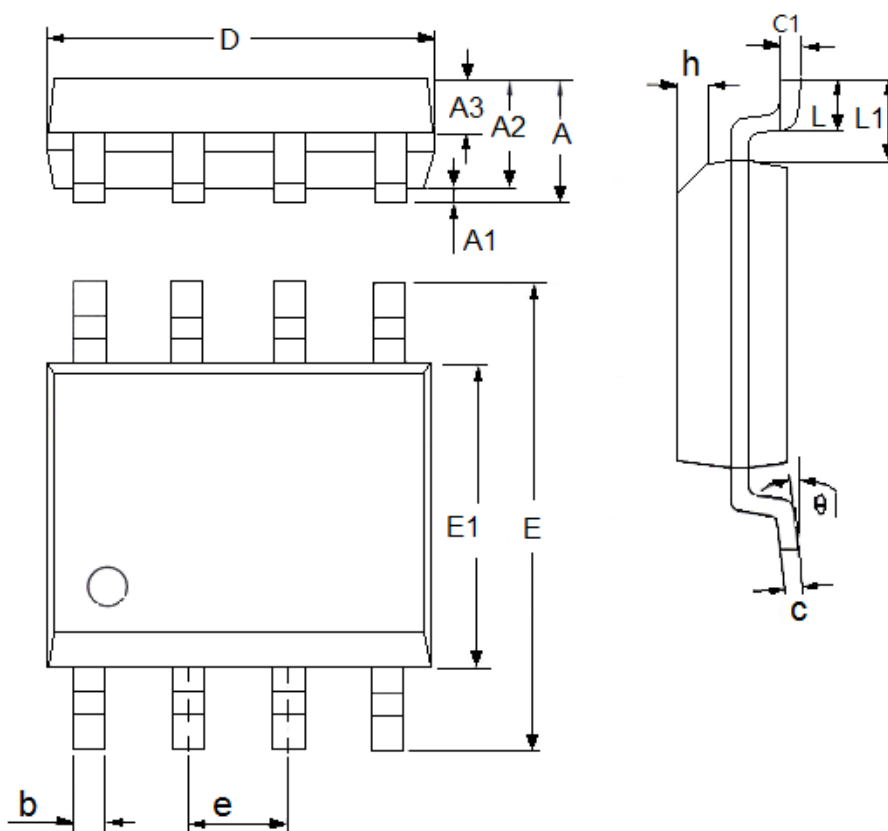
**Diode Reverse Recovery Waveform**



**Unclamped Inductive Switching Waveforms**

## Package Information

- Package Type:SOP8



DIM	Millimeters		Inches	
	Min	Max	Min	Max
A	1.3	1.8	0.0512	0.0709
A1	0.05	0.25	0.002	0.0098
A2	1.25	1.65	0.0492	0.065
A3	0.5	0.7	0.0197	0.0276
b	0.3	0.51	0.0118	0.0201
c	0.17	0.25	0.0067	0.0098
D	4.7	5.1	0.185	0.2008
E	5.8	6.2	0.2283	0.2441
E1	3.8	4	0.1496	0.1575
e	1.27(TYP)		0.05(TYP)	
h	0.25	0.5	0.0098	0.0197
L	0.4	1.27	0.0157	0.05
L1	1.04(TYP)		0.0409(TYP)	
θ	0	8°	0	8°
c1	0.25(TYP)		0.0098(TYP)	

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